

STP9NK65Z STP9NK65ZFP

N-channel 650 V, 1 Ω, 6.4 A, TO-220, TO-220FP Zener-protected SuperMESH[™] Power MOSFET

Features

Order codes	V _{DSS}	R _{DS(on)} max.	I _D	Pw
STP9NK65Z	650 V	< 1.2 Ω	6.4 A	125 W
STP9NK65ZFP	650 V	< 1.2 Ω	6.4 A	30 W

- 100% avalanche tested
- Low input capacitance and gate charge
- Low gate input resistance
- Extremely high dv/dt and avalanche capabilities

Applications

Switching applications

Description

These devices are N-channel Zener-protected Power MOSFETs developed using STMicroelectronics' SuperMESH[™] technology, achieved through optimization of ST's well established strip-based PowerMESH[™] layout. In addition to a significant reduction in onresistance, this device is designed to ensure a high level of dv/dt capability for the most demanding applications.

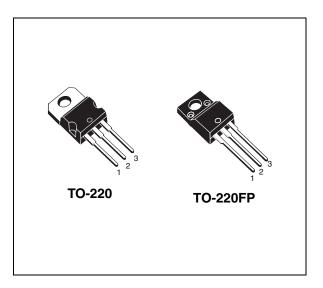


Figure 1. Internal schematic diagram

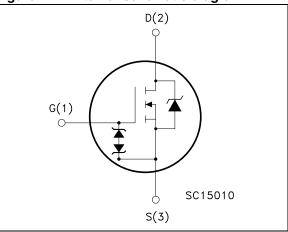


Table 1. Device summary

Order codes	Marking	Package	Packaging
STP9NK65Z	P9NK65Z	TO-220	Tube
STP9NK65ZFP	P9NK65ZFP	TO-220FP	Tube

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1 Electrical ratings

Table 2.	Absolute n	naximum	ratinas

Symbol	Parameter	Va	Unit	
Symbol	Falameter	TO-220	TO-220FP	Unit
V _{DS}	Drain-source voltage ($V_{GS} = 0$)	65	50	V
V _{GS}	Gate- source voltage	±	30	V
Ι _D	Drain current (continuous) at $T_C = 25 \text{ °C}$	6.4	6.4 ⁽¹⁾	А
Ι _D	Drain current (continuous) at T _C = 100 °C	4 4 ⁽¹⁾		А
I _{DM} ⁽²⁾	Drain current (pulsed)	25.6 25.6 ⁽¹⁾		А
P _{TOT}	Total dissipation at $T_{C} = 25 \ ^{\circ}C$	125	30	W
	Derating factor	1	0.24	W/°C
V _{ESD(G-S)}	Gate source ESD(HBM-C=100 pF, R=1.5 kΩ)	40	00	V
dv/dt ⁽³⁾	Peak diode recovery voltage slope	4.5		V/ns
V _{ISO}	Insulation withstand voltage (DC)	- 2500		V
Тj	Operating junction temperature	-55 to 150		°C
T _{stg}	Storage temperature	-55 to	o 150	°C

1. Limited only by maximum temperature allowed

2. Pulse width limited by safe operating area

3. I_{SD} \leq 6.4 A, di/dt \leq 200 A/µs, V_{DD} \leq 80%V_{(BR)DSS}

Table 3. Thermal data

Symbol	Parameter	Va	Unit	
Symbol	Falameter	TO-220	TO-220FP	Unit
R _{thj-case}	Thermal resistance junction-case max	1 4.2		°C/W
R _{thj-amb}	Thermal resistance junction-ambient max	62.5		°C/W
Τ _Ι	Maximum lead temperature for soldering purpose	300		°C

Table 4. Avalanche characteristics

Symbol	Parameter	Value	Unit
I _{AR}	Avalanche current, repetitive or not-repetitive (pulse width limited by $T_{j \text{ max}}$)	6.4	A
E _{AS}	Single pulse avalanche energy (starting T _j =25 °C, I _D =I _{AR} , V _{DD} =50 V)	200	mJ



2 Electrical characteristics

(T_{CASE}=25°C unless otherwise specified)

Table J.	On/on states					
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage (V _{GS} = 0)	I _D = 1 mA	650			v
I _{DSS}	Zero gate voltage drain current (V _{GS} = 0)	V _{DS} = 650 V V _{DS} = 650 V, @125 °C			1 50	μΑ μΑ
I _{GSS}	Gate-body leakage current (V _{DS} = 0)	V _{GS} = ± 20 V			±10	μA
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 100 \ \mu A$	3	3.75	4.5	V
R _{DS(on)}	Static drain-source on resistance	V _{GS} = 10 V, I _D = 3.2 A		1	1.2	Ω

Table 5. On/off states

Table 6. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
9 _{fs} ⁽¹⁾	Forward transconductance	$V_{DS} = 15 V_{,} I_{D} = 3.2 A$	-	6	-	S
C _{iss} C _{oss} C _{rss}	Input capacitance Output capacitance Reverse transfer capacitance	V _{DS} = 25 V, f = 1 MHz, V _{GS} = 0	-	1145 130 28	-	pF pF pF
C _{oss eq} ⁽²⁾ .	Equivalent output capacitance	$V_{GS} = 0, V_{DS} = 0$ to 400 V	-	55	-	pF
Q _g Q _{gs} Q _{gd}	Total gate charge Gate-source charge Gate-drain charge	$V_{DD} = 520 \text{ V}, \text{ I}_{D} = 6.4 \text{ A},$ $V_{GS} = 10 \text{ V}$ (see <i>Figure 3</i>)	-	41 7.5 22	-	nC nC nC

1. Pulsed: pulse duration=300µs, duty cycle 1.5%

2. $C_{oss~eq.}$ is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t _{d(on)} t _r	Turn-on delay time Rise time	$V_{DD} = 325 \text{ V}, \text{ I}_{D} = 3.2 \text{ A}$ $R_{G} = 4.7 \Omega V_{GS} = 10 \text{ V}$ (see <i>Figure 2</i>)	-	20 12	-	ns ns
t _{d(off)} t _f	Turn-off delay time Fall time	V_{DD} = 325 V, I _D = 3.2 A R _G = 4.7 Ω V _{GS} = 10 V (See <i>Figure 2</i>)	-	45 15	-	ns ns



Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I _{SD} I _{SDM} ⁽¹⁾	Source-drain current Source-drain current (pulsed)		-		6.4 25.6	A A
V _{SD} ⁽²⁾	Forward on voltage	$I_{SD} = 6.4 \text{ A}, V_{GS} = 0$	-		1.6	V
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	$I_{SD} = 6.4 \text{ A},$ di/dt = 100 A/µs $V_{DD} = 50 \text{ V}, \text{ T}_{j} = 150 ^{\circ}\text{C}$ (see <i>Figure 4</i>)	-	400 2600 13		ns nC A

Table 8.Source drain diode

1. Pulse width limited by safe operating area.

2. Pulsed: Pulse duration = $300 \ \mu$ s, duty cycle 1.5%

	Table 9.	Gate-source	zener	diode
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Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
BV _{GSO} ⁽¹⁾	Gate-source breakdown voltage	lgs=±1 mA (open drain)	30	-	-	V

 The built-in back-to-back Zener diodes have specifically been designed to enhance not only the device's ESD capability, but also to make them safely absorb possible voltage transients that may occasionally be applied from gate to source. In this respect the Zener voltage is appropriate to achieve an efficient and cost-effective intervention to protect the device's integrity. These integrated Zener diodes thus avoid the usage of external components.



3 Test circuits

Figure 2. Switching times test circuit for resistive load

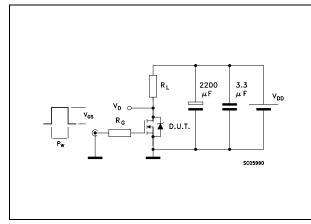
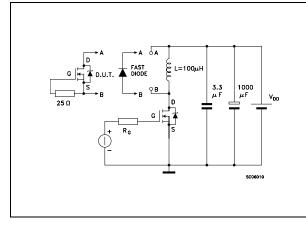


Figure 4. Test circuit for inductive load switching and diode recovery times





VDD 12\ 1KΩ 100nF I_G=CONST V; =20V=V_{GMAX} 100 Ω ¥ D.U.T. ()2200 μF 2.7ΚΩ ٧ -47KΩ 1KΩ SC06000

Gate charge test circuit

Figure 3.



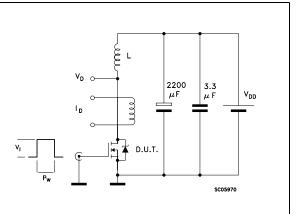
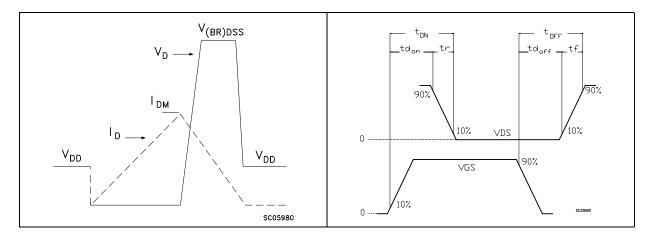


Figure 7. Switching time waveform





3.1 Electrical characteristics (curves)

Figure 9.

κ

10⁻¹

10-2

10-5

 $\delta = 0.5$

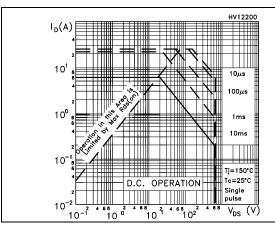
0.2

0.

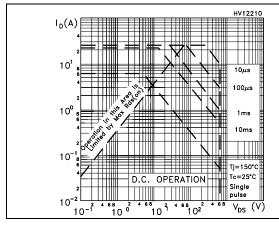
0.05

0.02

Figure 8. Safe operating area for TO-220











 10^{-3}

0.01

SINGLE PULSE

10-4

Thermal impedance for TO-220

 $Z_{th} = k R_{thJ-c}$

 $10^{-1} t_{p}(s)$

 $\delta = t_{\rm p} / \tau$

 10^{-2}

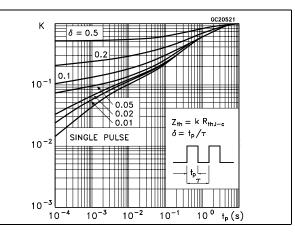


Figure 13. Transfer characteristics

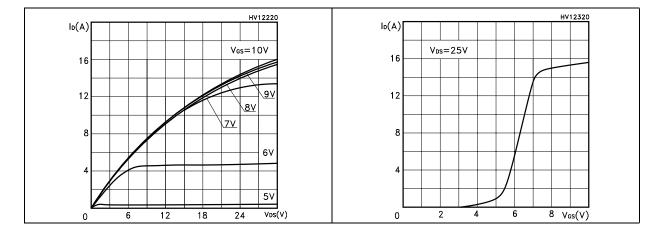




Figure 14. Transconductance

Figure 15. Static drain-source on resistance

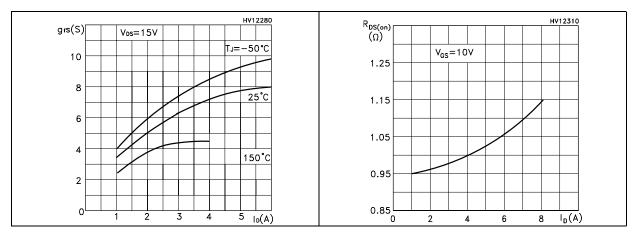


Figure 16. Gate charge vs gate-source voltage Figure 17. Capacitance variations

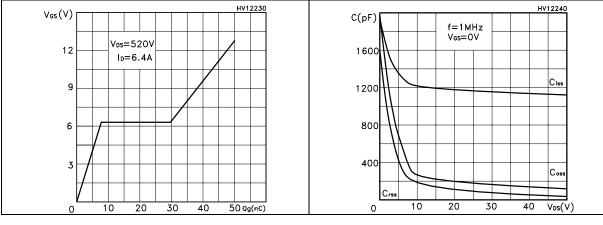


Figure 18. Normalized gate threshold voltage vs temperature

Figure 19. Normalized on resistance vs temperature

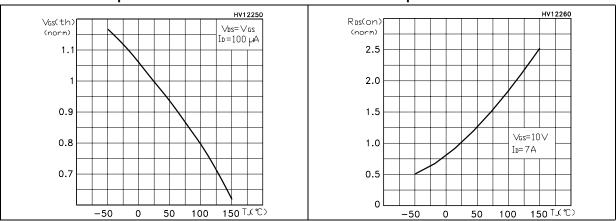




Figure 20. Source-drain diode forward characteristics

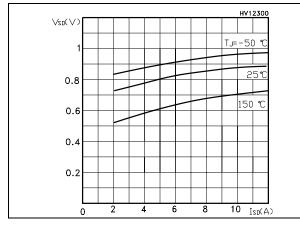


Figure 22. Maximum avalanche energy vs temperature

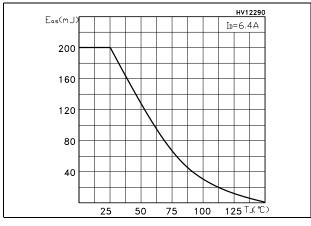
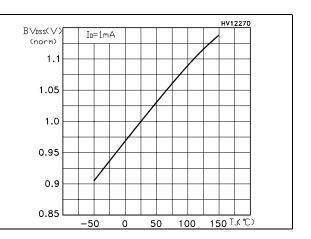


Figure 21. Normalized BV_{DSS} vs temperature



4 Package mechanical data

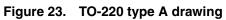
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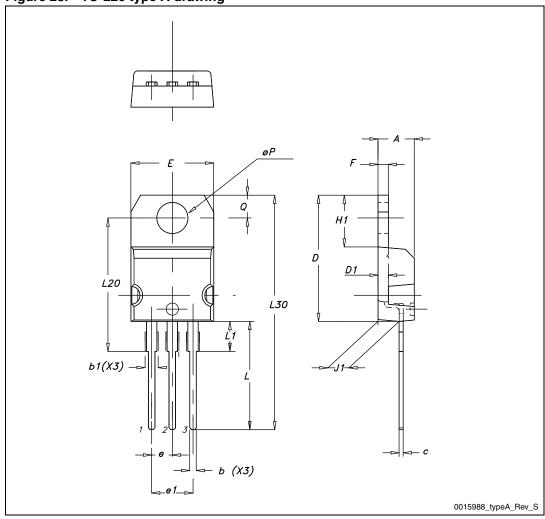


Table 10.	TO-220 type A mechanical data

Dim.			
	Min.	Тур.	Max.
А	4.40		4.60
b	0.61		0.88
b1	1.14		1.70
С	0.48		0.70
D	15.25		15.75
D1		1.27	
E	10		10.40
е	2.40		2.70
e1	4.95		5.15
F	1.23		1.32
H1	6.20		6.60
J1	2.40		2.72
L	13		14
L1	3.50		3.93
L20		16.40	
L30		28.90	
ØР	3.75		3.85
Q	2.65		2.95





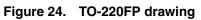


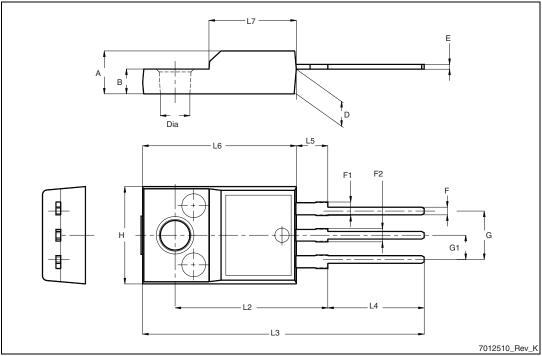


Dim.	mm			
	Min.	Тур.	Max.	
A	4.4		4.6	
В	2.5		2.7	
D	2.5		2.75	
E	0.45		0.7	
F	0.75		1	
F1	1.15		1.70	
F2	1.15		1.70	
G	4.95		5.2	
G1	2.4		2.7	
Н	10		10.4	
L2		16		
L3	28.6		30.6	
L4	9.8		10.6	
L5	2.9		3.6	
L6	15.9		16.4	
L7	9		9.3	
Dia	3		3.2	

Table 11. TO-220FP mechanical data









5 Revision history

Table 12. Document revision history

Date	Revision	Changes
11-Sep-2006	2	Complete version
19-Dec-2007	3	The document has been reformatted
26-Jan-2012	4	 Minor text changes Modified: <i>Features</i> in cover page Updated: <i>Section 4: Package mechanical data</i>



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